**PERFORMANCE CHECKSHEET**

Model: AVR-EB2A-B  
Type: Semiconductor Device Tester  
S.N.: 13513  
Date: February 8, 2017

Output Amplitude: to +100 mA, -100 mA  
Pulse Width (FWHM): 200 ns  
Switching Time, + to -, 10%-90%: \(\leq 300\) ps (at mainframe)  
PRF: 1 - 10 kHz  
Jitter, Stability: OK  
Prime Power: 100-240V AC, 50-60 Hz.

**Test Waveforms**

With a 1N4148 installed in the AVX-CA-AR1 test jig, 40 mA/div, 2 ns/div:

\[I_F = +100\ mA, \ I_R = -100\ mA\]

Measured \(t_{RR}\) = 9.2 ns.

With a 1N5811US installed in the AVX-CA-AR1 test jig, 40 mA/div, 10 ns/div:

\[I_F = +100\ mA, \ I_R = -100\ mA\]

Measured \(t_{RR}\) = 53 ns.
Same as previous, scaled to showing switching time, 1N5811US installed in the AVX-CA-AR1 test jig, 40 mA/div, 5 ns/div:

-24V pulse output directly from mainframe, with the test jig bypassed (5 V/div, 1 ns/div):

Shows a 10%-90% transition time of < 700 ps.  
Shows a 10%-90% transition time of < 200 ps.